



3.3V FULL-DUPLEX RS-485 DRIVERS AND RECEIVERS

FEATURES

- 1/8 Unit-Load Option Available (Up to 256 Nodes on the Bus)
- Bus-Pin ESD Protection Exceeds 15 kV HBM
- Optional Driver Output Transition Times for Signaling Rates⁽¹⁾ of 1 Mbps, 5 Mbps and 25 Mbps
- Low-Current Standby Mode: < 1 μA
- Glitch-Free Power-Up and Power-Down Protection for Hot-Plugging Applications
- 5-V Tolerant Inputs
- . Bus Idle, Open, and Short Circuit Failsafe
- Driver Current Limiting and Thermal Shutdown
- Meets or exceeds the requirements of ANSI TIA/EIA-485-A and RS-422 Compatible
- 5-V Devices available, SN65HVD50-59
- (1) The signaling rate of a line is the number of voltage transitions that are made per second expressed in the units bps (bits per second).

APPLICATIONS

- Utility Meters
- DTE/DCE Interfaces
- Industrial, Process, and Building Automation
- Point-of-Sale (POS) Terminals and Networks

DESCRIPTION

The SN65HVD3X devices are 3-state differential line drivers and differential-input line receivers that operate with 3.3-V power supply.

Each driver and receiver has separate input and output pins for full-duplex bus communication designs. They are designed for balanced transmission lines and interoperation with ANSI TIA/EIA-485A, TIA/EIA-422-B, ITU-T v.11 and ISO 8482:1993 standard-compliant devices.

The SN65HVD30, SN65HVD31, SN65HVD32, SN65HVD36 and SN65HVD37 are fully enabled with no external enabling pins. The SN65HVD36 and SN65HVD37 implement receiver equalization technology for improved performance in long distance applications.

The SN65HVD33, SN65HVD34, SN65HVD35, SN65HVD38, and SN65HVD39 have active-high driver enables and active-low receiver enables. A very low, less than 1μ A, standby current can be achieved by disabling both the driver and receiver. The SN65HVD38 and SN65HVD39 implement receiver equalization technology for improved performance in long distance applications.

All devices are characterized for operation from -40°C to 85°C.

The SN65HVD36 and SN65HVD38 implement receiver equalization technology for improved jitter performance on differential bus applications with data rates up to 20 Mbps at cable lengths up to 160 meters.

The SN65HVD37 and SN65HVD39 implement receiver equalization technology for improved jitter performance on differential bus applications with data rates in the range of 1 to 5 Mbps at cable lengths up to 1000 meters.

IMPROVED REPLACEMENT FOR:

Part Number	Replace with	
xxx3491 xxx3490	SN65HVD33: SN65HVD30:	Better ESD protection (15kV vs 2kV or not specified) Higher Signaling Rate (25Mbps vs 20Mbps) Fractional Unit Load (64 Nodes vs 32)
MAX3491E MAX3490E	SN65HVD33: SN65HVD30:	Higher Signaling Rate (25Mbps vs 12Mbps) Fractional Unit Load (64 Nodes vs 32)
MAX3076E MAX3077E	SN65HVD33: SN65HVD30:	Higher Signaling Rate (25Mbps vs 16Mbps) Lower Standby Current (1 μA vs 10 μA)
MAX3073E MAX3074E	SN65HVD34: SN65HVD31:	Higher Signaling Rate (5Mbps vs 500kbps) Lower Standby Current (1 μ A vs 10 μ A)
MAX3070E MAX3071E	SN65HVD35: SN65HVD32:	Higher Signaling Rate (1Mbps vs 250kbps) Lower Standby Current (1 μA vs 10 μA)



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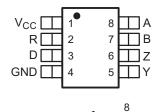


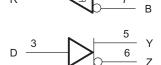
This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

SN65HVD30, SN65HVD31, SN65HVD32, SN65HVD36, SN65HVD37

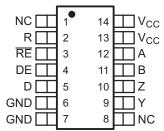
D PACKAGE (TOP VIEW)



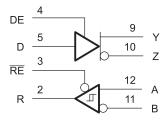


SN65HVD33, SN65HVD34, SN65HVD35, SN65HVD38, SN65HVD39

D PACKAGE (TOP VIEW)



NC - No internal connection



AVAILABLE OPTIONS

SIGNALING RATE	UNIT LOADS	RECEIVER EQUALIZATION	ENABLES	BASE PART NUMBER	SOIC MARKING
25 Mbps	1/2	No	No	SN65HVD30	65HVD30
5 Mbps	1/8	No	No	SN65HVD31	65HVD31
1 Mbps	1/8	No	No	SN65HVD32	65HVD32
25 Mbps	1/2	No	Yes	SN65HVD33	65HVD33
5 Mbps	1/8	No	Yes	SN65HVD34	65HVD34
1 Mbps	1/8	No	Yes	SN65HVD35	65HVD35
25 Mbps	1/2	Yes	No	SN65HVD36	PREVIEW
5 Mbps	1/8	Yes	No	SN65HVD37	PREVIEW
25 Mbps	1/2	Yes	Yes	SN65HVD38	PREVIEW
5 Mbps	1/8	Yes	Yes	SN65HVD39	PREVIEW



ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted (1)(2)

		UNIT
V_{CC}	Supply voltage range	–0.3 V to 6 V
$V_{(A)}, V_{(B)}, V_{(Y)}, V_{(Z)}$	Voltage range at any bus terminal (A, B, Y, Z)	–9 V to 14 V
V _(TRANS)	Voltage input, transient pulse through 100 Ω . See Figure 12 (A, B, Y, Z) ⁽³⁾	–50 to 50 V
V _I	Input voltage range (D, DE, RE)	-0.5 V to 7 V
P _{D(cont)}	Continuous total power dissipation	Internally limited ⁽⁴⁾
Io	Output current (receiver output only, R)	11 mA

⁽¹⁾ Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range unless otherwise noted

				MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage			3		3.6	V
V _I or V _{IC}	Voltage at any bus	s terminal (sep	nal (separately or common mode)			12	V
		SN65HVD30	, SN65HVD33, SN65HVD36, SN65HVD38			25	
1/t _{UI}	Signaling rate	SN65HVD31	, SN65HVD34, SN65HVD37, SN65HVD39			5	Mbps
		SN65HVD32	, SN65HVD35			1	
R_L	Differential load re	sistance		54	60		Ω
V_{IH}	High-level input vo	ltage	D, DE, RE	2		V_{CC}	
V_{IL}	Low-level input vol	ltage	D, DE, RE	0		0.8	V
V _{ID}	Differential input v	oltage		-12		12	
	LP ale la cal action to		Driver	-60			1
I _{OH}	High-level output of	current	Receiver	-8			mA
			Driver			60	A
l _{OL}	Low-level output c	urrent	Receiver			8	mA
T _A	Ambient still-air ter	mperature		-40		85	°C

⁽¹⁾ The algebraic convention, in which the least positive (most negative) limit is designated as minimum is used in this data sheet.

ELECTROSTATIC DISCHARGE PROTECTION

PARAMETER	TEST CONDITIONS	MIN TYP(1)	MAX	UNIT
Human body model	Bus terminals and GND	±16		
Human body model ⁽²⁾	All pins	±4		kV
Charged-device-model (3)	All pins	±1		

⁽¹⁾ All typical values at 25°C with 3.3-V supply.

All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

This tests survivability only and the output state of the receiver is not specified.

The thermal shutdown protection circuit internally limits the continuous total power dissipation. Thermal shutdown typically occurs when the junction temperature reaches 165°C.

 ⁽²⁾ Tested in accordance with JEDEC Standard 22, Test Method A114-A.
 (3) Tested in accordance with JEDEC Standard 22, Test Method C101.



DRIVER ELECTRICAL CHARACTERISTICS

PARAMETER			TEST CONDITI	ONS	MIN	TYP ⁽¹⁾	MAX	UNIT		
V _{I(K)}	Input clamp voltage		$I_1 = -18 \text{ mA}$		-1.5			V		
, ,			$I_{O} = 0$	$I_{O} = 0$			V _{CC}			
11/	Ctoody atota differen	atial autout valtage	$R_L = 54 \Omega$, See Figure 1 (RS-	485)	1.5	2		V		
$ V_{OD(SS)} $	Steady-state differer	iliai output voitage	$R_L = 100 \Omega$, See Figure 1, (2)	(RS-422)	2	2.3		V		
	· ·		$V_{\text{test}} = -7 \text{ V to } 12 \text{ V, See Figure}$	ire 2	1.5					
$\Delta V_{OD(SS)} $	Change in magnitud differential output vo states		$R_L = 54 \Omega$, See Figure 1 and	Figure 2	-0.2		0.2	٧		
V _{OD(RING)}	Differential Output V and undershoot	oltage overshoot	$R_L = 54 \Omega$, $C_L = 50 pF$, See F Figure 3	igure 5 and			10%(3)	V		
	Peak-to-peak	HVD30, HVD33, HVD36, HVD38	See Figure 4					0.5		
V _{OC(PP)}	common-mode output voltage	HVD31, HVD34, HVD37, HVD39, HVD32, HVD35				0.25		V		
V _{OC(SS)}	Steady-state commo voltage	on-mode output	Coo Figure 4		1.6		2.3	V		
$\Delta V_{OC(SS)}$	Change in steady-st output voltage	ate common-mode	See Figure 4		-0.05		0.05	V		
		HVD30, HVD31,	$V_{CC} = 0 \text{ V}, V_Z \text{ or } V_Y = 12 \text{ V},$ Other input at 0 V				90			
$I_{Z(Z)}$ or	High-impedance	HVD32, HVD36, HVD37	$V_{CC} = 0 \text{ V}, V_Z \text{ or } V_Y = -7 \text{ V},$ Other input at 0 V		-10			μΑ		
$I_{Y(Z)}^{-(-)}$	state output current	HVD33, HVD34, HVD35, HVD38,	$V_{CC} = 3 \text{ V or } 0 \text{ V, DE} = 0 \text{ V}$ $V_Z \text{ or } V_Y = 12 \text{ V}$	Other input			90	μΑ		
		HVD39	$V_{CC} = 3 \text{ V or } 0 \text{ V, DE} = 0 \text{ V}$ $V_Z \text{ or } V_Y = -7 \text{ V}$	at 0 V	-10					
I _{Z(S)} or	Chart Circuit autaut	V_Z or $V_Y = -7$ V Other input		Other input	-250		250	A		
I _{Y(S)}	Short Circuit output	Current	V_Z or $V_Y = 12 V$	at 0 V	-250 2		250	mA		
I _I	Input current	D, DE			0		100	μΑ		
C _(OD)	Differential output ca	apacitance	$V_{OD} = 0.4 \sin (4E6\pi t) + 0.5 V$, DE at 0 V		16		pF		

⁽¹⁾ All typical values are at 25°C and with a 3.3-V supply.
(2) V_{CC} is 3.3 Vdc ± 5%
(3) 10% of the peak-to-peak differential output voltage swing, per TIA/EIA-485



DRIVER SWITCHING CHARACTERISTICS

	PARAM	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT			
	-	HVD30, HVD33, HVD36, HVD38		4	10	18			
t_{PLH}	Propagation delay time, low-to-high-level output	HVD31, HVD34, HVD37, HVD39		25	38	65	ns		
	iow to riight lovel eatpat	HVD32, HVD35		120	175	305			
		HVD30, HVD33, HVD36, HVD38		4	9	18			
t _{PHL}	Propagation delay time, high-to-low-level output	HVD31, HVD34, HVD37, HVD39		25	38	65	ns		
	riigii to low level output	HVD32, HVD35		120	175	305			
		HVD30, HVD33, HVD36, HVD38		2.5	5	12			
t _r	Differential output signal rise time	HVD31, HVD34, HVD37, HVD39	$R_L = 54 \Omega$, $C_L = 50 pF$, See Figure 5	20	37	60	ns		
	une	HVD32, HVD35	occ riguic s	120	185	300			
		HVD30, HVD33, HVD36, HVD38		2.5	5	12			
t _f	Differential output signal fall time	HVD31, HVD34, HVD37, HVD39		20	35	60	ns		
	ume	HVD32, HVD35		120	180	300			
		HVD30, HVD33, HVD36, HVD38	_		0.6				
t _{sk(p)}	Pulse skew (t _{PHL} - t _{PLH})	HVD31, HVD34, HVD37, HVD39			2.0		ns		
		HVD32, HVD35	_		5.1				
	Propagation delay time,	HVD33, HVD38				45	ns		
t _{PZH1}	high-impedance-to-high-level	HVD34, HVD39	B 440.0 DE 40.4			235			
	output	HVD35	$R_L = 110 \Omega$, \overline{RE} at 0 V, D = 3 V and S1 = Y, or			490			
	Propagation delay time,	HVD33, HVD38	D = 0 V and S1 = Z			25			
t _{PHZ}	high-level-to-high-impedance	HVD34, HVD39	See Figure 6			65	ns		
	output	HVD35	_			165			
	Propagation delay time,	HVD33, HVD38				35			
t _{PZL1}	high-impedance-to-low-level	HVD34, HVD39	D 440 0 DE -1 0 V			190	ns		
	output	HVD35	$R_L = 110 \Omega$, \overline{RE} at 0 V, D = 3 V and S1 = Z. or			490			
	Propagation delay time,	HVD33, HVD38	D = 0 V and S1 = Y		D = 0 V and S1 = Y			30	
t_{PLZ}	low-level-to-high-impedance	HVD34, HVD39	See Figure 7			120	ns		
	output	HVD35				290			
t _{PZH2}	Propagation delay time, standb	y-to-high-level output	$R_L = 110 \Omega$, \overline{RE} at 3 V, D = 3 V and S1 = Y, or D = 0 V and S1 = Z See Figure 6			4000	ns		
t _{PZL2}	Propagation delay time, standb	y-to-low-level output	$R_L = 110 \ \Omega$, \overline{RE} at 3 V, D = 3 V and $S1 = Z$, or D = 0 V and $S1 = YSee Figure 7$			4000	ns		

⁽¹⁾ All typical values are at 25°C and with a 3.3-V supply.



RECEIVER ELECTRICAL CHARACTERISTICS

	PARAME	TER	TEST CONDITIO	NS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{IT+}	Positive-going differer voltage	ntial input threshold	I _O = -8 mA	I _O = -8 mA			-0.02	.,
V _{IT-}	Negative-going differe voltage	ential input threshold	I _O = 8 mA		-0.20			V
V_{hys}	Hysteresis voltage (V _I	_{T+} - V _{IT-})				50		mV
V _{IK}	Enable-input clamp vo	oltage	I _I = -18 mA		-1.5			V
	0		V_{ID} = 200 mV, I_{O} = -8 mA, See Figure 8		2.4			.,
Vo	Output voltage		$V_{ID} = -200 \text{ mV}, I_{O} = 8 \text{ mA}, \text{ See Figure 8}$				0.4	V
$I_{O(Z)}$	High-impedance-state	output current	$V_O = 0$ or V_{CC} , \overline{RE} at V_{CC}		-1		1	μA
			V_A or $V_B = 12 \text{ V}$			0.05	0.1	
		HVD31, HVD32,	V_{A} or $V_{B} = 12 \text{ V}, V_{CC} = 0 \text{ V}$	Other input		0.06	0.1	
		HVD34, HVD35, HVD37, HVD39	V_A or $V_B = -7 \text{ V}$	at 0V	-0.10	-0.04		mA
I _A or			V_A or $V_B = -7$ V, $V_{CC} = 0$ V		-0.10	-0.03		
I _B	Bus input current		V_A or $V_B = 12 \text{ V}$			0.20	0.35	
		HVD30, HVD33,	V_A or $V_B = 12 \text{ V}, V_{CC} = 0 \text{ V}$	Other input		0.24	0.4	mA
		HVD36, HVD38	V_A or $V_B = -7 \text{ V}$	at 0V	-0.35	-0.18		
			V_A or $V_B = -7$ V, $V_{CC} = 0$ V		-0.25	-0.13		
I _{IH}	Input current, RE		V _{IH} = 0.8 V or 2 V		-60			μA
C _{ID}	Differential input capa	citance	$V_{ID} = 0.4 \sin (4E6\pi t) + 0.5 V,$	DE at 0 V		15		pF
Suppl	y Current				l			
		HVD30					2.1	
		HVD31, HVD32	D at 0 V or V _{CC} and No Load				6.4	mA
		HVD36, HVD37					7.9	
		HVD33	RE at 0 V, D at 0 V or V _{CC} , D	E at 0 V			1.8	
		HVD34, HVD35	No load (Receiver enabled ar	nd driver			2.2	mA
		HVD38, HVD39	disabled)				3.8	
		HVD33, HVD34, HVD35, HVD38, HVD39	RE at V _{CC} , D at V _{CC} , DE at 0 No load (Receiver disabled andisabled)	V, nd driver		0.022	1	μΑ
I_{CC}	Supply current	HVD33	·				2.1	
			RE at 0 V, D at 0 V or V _{CC} , D				6.5	
		HVD38	 No load (Receiver enabled ar enabled) 	nd driver			3.5	
		HVD39	enableu)				8	
		HVD33					1.8	mA
		HVD34, HVD35	RE at V _{CC} , D at 0 V or V _{CC} , D	DE at V _{CC}			6.2	
		No lo		No load (Receiver disabled and driver enabled)			2.5	
		HVD39					7	

⁽¹⁾ All typical values are at 25°C and with a 3.3-V supply.



RECEIVER SWITCHING CHARACTERISTICS

over recommended operating conditions unless otherwise noted

	PARA	METER	TEST (CONDITIONS	MIN TYP(1)	MAX	UNIT	
	Drangation delay time	HVD30, HVD33, HVD36, HVD38			26	45		
t _{PLH}	Propagation delay time, low-to-high-level output	HVD31, HVD32, HVD34, HVD35, HVD37, HVD39]		47	70		
	Drangation delay time	HVD30, HVD33, HVD36, HVD38			29	45		
t _{PHL}	Propagation delay time, high-to-low-level output	HVD31, HVD32, HVD34, HVD35, HVD37, HVD39	V _{ID} = -1.5 V	V _{ID} = -1.5 V to 1.5 V,		70		
t _{sk(p)}	Pulse skew (t _{PHI} – t _{PI H})	HVD30, HVD33, HVD36, HVD37, HVD38, HVD39	C _L = 15 pF, See Figure 9			7		
On(p)		HVD31, HVD34, HVD32, HVD35				10	ns	
t _r	Output signal rise time					5	115	
t _f	Output signal fall time				6			
t _{PHZ}	Output disable time from hi	gh level	DE at 3 V	_	20			
t _{PZH1}	Output enable time to high	level	DE at 3 V	$C_L = 15 \text{ pF},$ See Figure 10				
t _{PZH2}	Propagation delay time, sta	ndby-to-high-level output	DE at 0 V		400			
t _{PLZ}	Output disable time from lo	w level	55			20		
t _{PZL1}	Output enable time to low le	evel	DE at 3 V C _L = 15 pF, See Figure 11		OL = 13 pi ,		20	
t _{PZL2}	Propagation delay time, sta	ndby-to-low-level output	DE at 0 V	_ ccc : iguio i i		4000		

⁽¹⁾ All typical values are at 25°C and with a 3.3-V supply

RECEIVER EQUALIZATION CHARACTERISTICS

F	PARAMETER	TEST CONDI	TIONS		DEVICE	MIN TYP ⁽¹⁾	MAX	UNIT						
				0 m	HVD36, HVD38	PREVIEW								
				100	HVD33 ⁽²⁾	PREVIEW								
		25 Mb							100 111	100 111	HVD36, HVD38	PREVIEW		
				HVD33 ⁽²⁾	PREVIEW									
				130 111	HVD36, HVD38	PREVIEW								
			200 m	HVD33 ⁽²⁾	PREVIEW									
				200 111	HVD36, HVD38	PREVIEW								
				200 m	HVD33 ⁽²⁾	PREVIEW								
			10 Mbps		200	200 111	HVD36, HVD38	PREVIEW						
				250 m	HVD33 ⁽²⁾	PREVIEW								
t _{j(pp)}	Peak-to-peak eye-pattern jitter			250 111	HVD36, HVD38	PREVIEW		ns						
	oyo pano j.no.		2 ¹⁶ –1, Belden 3105A cable	2 ¹⁶ –1, Belden 3105A cable	2 ¹⁶ –1, Belden 3105A cable		300 m	HVD33 ⁽²⁾	PREVIEW					
					300	300 111	HVD36, HVD38	PREVIEW						
			E Mbpo	500 m	HVD34 ⁽²⁾	PREVIEW								
		5 Mbps 500 r	300 111	HVD37, HVD39	PREVIEW									
					HVD33 ⁽²⁾	PREVIEW								
			2 Mbps	500 m	HVD34 ⁽²⁾	PREVIEW								
			3 Mbps	500 III	HVD36, HVD38	PREVIEW								
					HVD37, HVD39	PREVIEW								
			1 Mbps	1000 m	HVD34 ⁽²⁾	PREVIEW								
			i ivibps	1000 111	HVD37, HVD39	PREVIEW								

 ⁽¹⁾ All typical values are at V_{CC} = 5 V, and temperature = 25°C.
 (2) The HVD33 and the HVD34 do not have receiver equalization but are specified for comparison.

SN65HVD30 - SN65HVD39





DEVICE POWER DISSIPATION – P_{D}

TEST CONDITIONS	DEVICE	MIN	TYP MA	UNIT
	HVD30, HVD36 (25 Mbps)		19	7
$R_L = 60$, $C_L = 50$ pF, Input to D a 50% duty cycle square wave at indicated signaling rate $T_A = 85^{\circ}$ C	HVD31, HVD37 (5 Mbps)		21	3 mW
indicated signaling rate 1 _A = 00 0	HVD32 (1 Mbps)		19	3
	HVD33, HVD38 (25 Mbps)		19	7
$R_L = 60$, $C_L = 50$ pF, DE at VCC, \overline{RE} at 0 V, Input to D a 50% duty cycle square wave at indicated signaling rate $T_A = 85$ °C	HVD34, HVD39 (5 Mbps)		19	3 mW
auty syste square trave at maleated signaling rate 14 = 00 0	HVD35 (1 Mbps)		24	3



PARAMETER MEASUREMENT INFORMATION

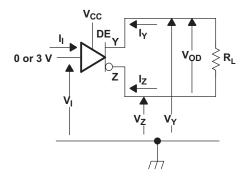


Figure 1. Driver V_{OD} Test Circuit and Voltage and Current Definitions

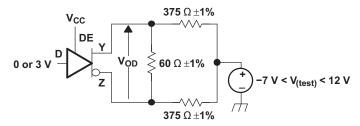


Figure 2. Driver V_{OD} With Common-Mode Loading Test Circuit

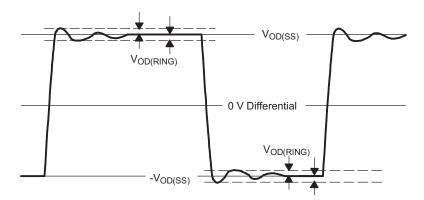
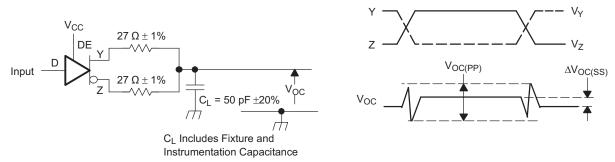


Figure 3. V_{OD(RING)} Waveform and Definitions

 $V_{\text{OD(RING)}}$ is measured at four points on the output waveform, corresponding to overshoot and undershoot from the $V_{\text{OD(H)}}$ and $V_{\text{OD(L)}}$ steady state values.

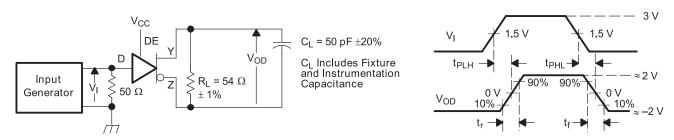


Input: PRR = 500 kHz, 50% Duty Cycle,t $_{r}$ <6ns, t_{f} <6ns, Z_{O} = 50 Ω

Figure 4. Test Circuit and Definitions for the Driver Common-Mode Output Voltage



PARAMETER MEASUREMENT INFORMATION (continued)



Generator: PRR = 500 kHz, 50% Duty Cycle, t_r <6 ns, t_f <6 ns, Z_o = 50 Ω

Figure 5. Driver Switching Test Circuit and Voltage Waveforms

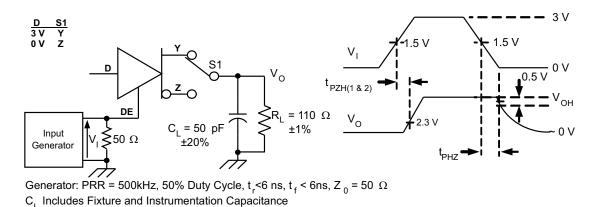


Figure 6. Driver High-Level Output Enable and Disable Time Test Circuit and Voltage Waveforms

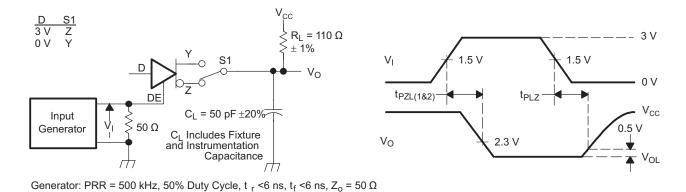


Figure 7. Driver Low-Level Output Enable and Disable Time Test Circuit and Voltage Waveforms

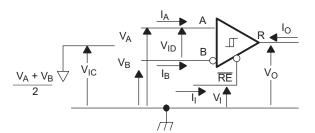


Figure 8. Receiver Voltage and Current Definitions



PARAMETER MEASUREMENT INFORMATION (continued)

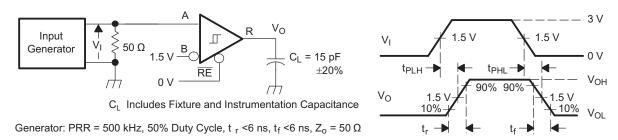


Figure 9. Receiver Switching Test Circuit and Voltage Waveforms

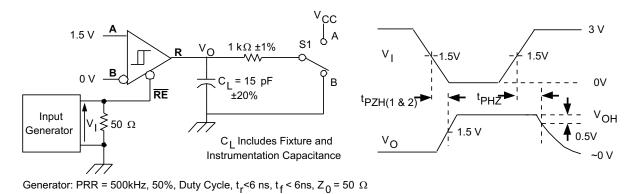
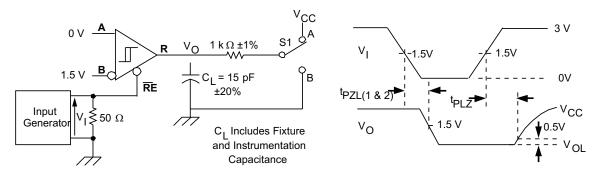


Figure 10. Receiver High-Level Enable and Disable Time Test Circuit and Voltage Waveforms



Generator: PRR = 500 kHz, 50% Duty Cycle, t_r <6 ns, t_f < 6ns, Z_0 = 50 Ω

Figure 11. Receiver Enable Time From Standby (Driver Disabled)

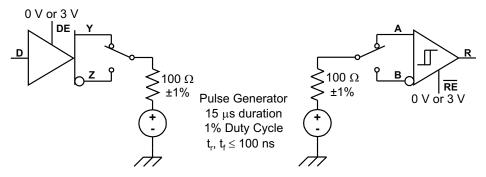


Figure 12. Test Circuit, Transient Over Voltage Test

DEVICE INFORMATION

LOW-POWER STANDBY MODE

When both the driver and receiver are disabled (DE low and \overline{RE} high) the device is in standby mode. If the enable inputs are in this state for less than 60 ns, the device does not enter standby mode. This guards against inadvertently entering standby mode during driver/receiver enabling. Only when the enable inputs are held in this state for 300 ns or more, the device is assured to be in standby mode. In this low-power standby mode, most internal circuitry is powered down, and the supply current is typically less than 1 nA. When either the driver or the receiver is re-enabled, the internal circuitry becomes active.

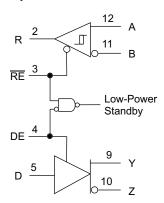


Figure 13. Low-Power Standby Logic Diagram

If only the driver is re-enabled (DE transitions to high) the driver outputs are driven according to the D input after the enable times given by t_{PZH2} and t_{PZL2} in the driver switching characteristics. If the D input is open when the driver is enabled, the driver outputs defaults to A high and B low, in accordance with the driver failsafe feature.

If only the receiver is re-enabled (\overline{RE} transitions to low) the receiver output is driven according to the state of the bus inputs (A and B) after the enable times given by t_{PZH2} and t_{PZL2} in the receiver switching characteristics. If there is no valid state on the bus the receiver responds as described in the failsafe operation section.

If both the receiver and driver are re-enabled simultaneously, the receiver output is driven according to the state of the bus inputs (A and B) and the driver output is driven according to the D input. Note that the state of the active driver affects the inputs to the receiver. Therefore, the receiver outputs are valid as soon as the driver outputs are valid.



DEVICE INFORMATION (continued)

FUNCTION TABLES

SN65HVD33, SN65HVD34, SN65HVD35, SN65HVD38, SN65HVD39 DRIVER

IN	PUTS	OUTPUTS		
D	DE	Y	Z	
Н	Н	Н	L	
L	Н	L	Н	
X	L or open	Z	Z	
Open	Н	L	Н	

SN65HVD33, SN65HVD34, SN65HVD35, SN65HVD38, SN65HVD39 RECEIVER

DIFFERENTIAL INPUTS $V_{ID} = V_{(A)} - V_{(B)}$	ENABLE RE	OUTPUT R
$V_{ID} \leq -0.2 \text{ V}$	L	L
$-0.2 \text{ V} < \text{V}_{\text{ID}} < -0.02 \text{ V}$	L	?
-0.02 V ≤ V _{ID}	L	Н
X	H or open	Z
Open Circuit	L	Н
Idle circuit	L	Н
Short Circuit, V _(A) = V _(B)	L	Н

SN65HVD30, SN65HVD31, SN65HVD32, SN65HVD36, SN65HVD37 DRIVER

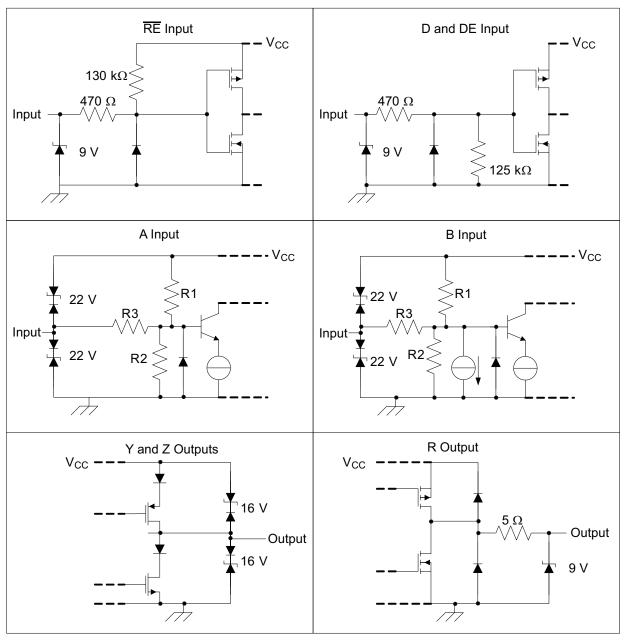
	OUTPUTS					
INPUT D	Y	Z				
Н	Н	L				
L	L	Н				
Open	L	Н				

SN65HVD30, SN65HVD31, SN65HVD32, SN65HVD36, SN65HVD37 RECEIVER

DIFFERENTIAL INPUTS $V_{ID} = V_{(A)} - V_{(B)}$	OUTPUT R
$V_{ID} \leq -0.2 \text{ V}$	L
$-0.2 \text{ V} < \text{V}_{\text{ID}} < -0.02 \text{ V}$?
-0.02 V ≤ V _{ID}	Н
Open Circuit	Н
Idle circuit	Н
Short Circuit, V _(A) = V _(B)	Н



EQUIVALENT INPUT AND OUTPUT SCHEMATIC DIAGRAMS

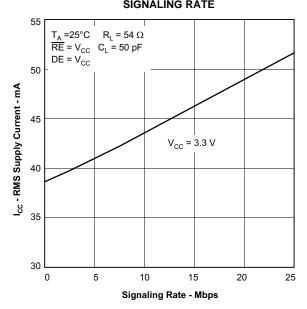


	R1/R2	R3
SN65HVD30, SN65HVD33, SN65HVD36, SN65HVD38	9 kΩ	45 kΩ
SN65HVD31, SN65HVD32, SN65HVD34, SN65HVD35 SN65HVD37, SN65HVD38, SN65HVD39	36 kΩ	180 kΩ



TYPICAL CHARACTERISTICS

HD30, HD33 RMS SUPPLY CURRENT vs SIGNALING RATE



HD31, HD34 RMS SUPPLY CURRENT VS SIGNALING RATE

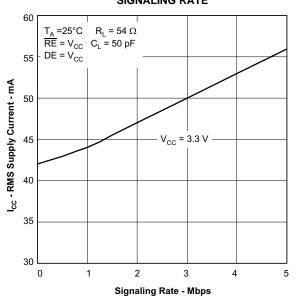


Figure 14.

Figure 15.

HD32, HD35 RMS SUPPLY CURRENT vs SIGNALING RATE

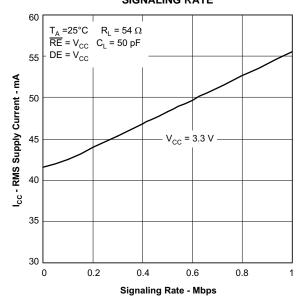


Figure 16.



TYPICAL CHARACTERISTICS (continued)

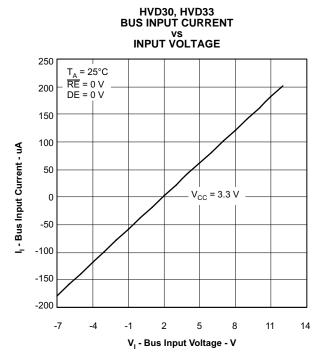


Figure 17.

DRIVER LOW-LEVEL OUTPUT CURRENT

vs LOW-LEVEL OUTPUT VOLTAGE 0.14 V_{CC} = 3.3 V $DE = V_{CC}$ 0.12 D = 0 VIoL - Low-level Output Current - A 0.1 0.08 0.06

V_{OL} - Low-Level Output Voltage - V Figure 19.

1.5

2

2.5

3

3.5



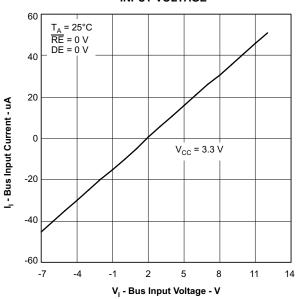


Figure 18.

DRIVER HIGH-LEVEL OUTPUT CURRENT vs HIGH-LEVEL OUTPUT VOLTAGE

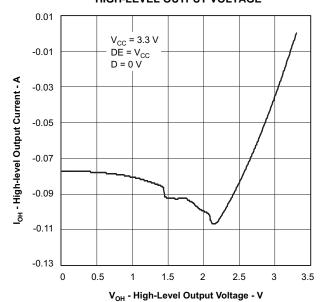


Figure 20.

0.04

0.02

-0.02

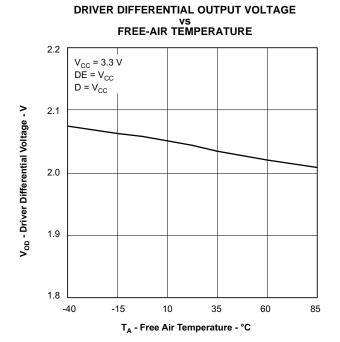
0

0

0.5



TYPICAL CHARACTERISTICS (continued)



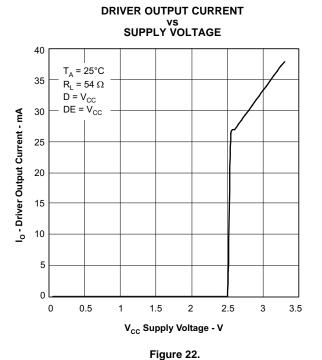


Figure 21.

ENABLE TIME
VS
COMMON-MODE VOLTAGE (SEE Figure 24)

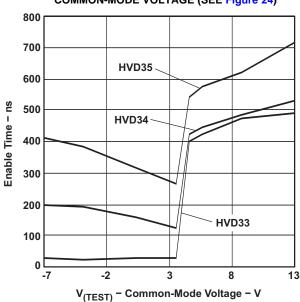


Figure 23.



TYPICAL CHARACTERISTICS (continued)

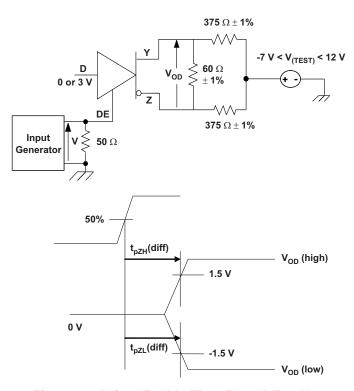


Figure 24. Driver Enable Time From DE to $V_{\rm OD}$

The time $t_{pZL}(x)$ is the measure from DE to $V_{OD}(x)$. V_{OD} is valid when it is greater than 1.5 V.



PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
SN65HVD30D	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD30DG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD30DR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD30DRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD31D	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD31DG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD31DR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD31DRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD32D	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD32DG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD32DR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD32DRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD33D	ACTIVE	SOIC	D	14	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD33DG4	ACTIVE	SOIC	D	14	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD33DR	ACTIVE	SOIC	D	14	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD33DRG4	ACTIVE	SOIC	D	14	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD34D	ACTIVE	SOIC	D	14	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD34DG4	ACTIVE	SOIC	D	14	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD34DR	ACTIVE	SOIC	D	14	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD34DRG4	ACTIVE	SOIC	D	14	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD35D	ACTIVE	SOIC	D	14	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD35DG4	ACTIVE	SOIC	D	14	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD35DR	ACTIVE	SOIC	D	14	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD35DRG4	ACTIVE	SOIC	D	14	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM

 $^{^{(1)}}$ The marketing status values are defined as follows:



PACKAGE OPTION ADDENDUM

21-Mar-2007

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

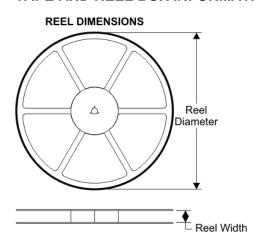
(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

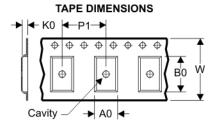
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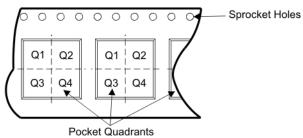
TAPE AND REEL BOX INFORMATION





	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



Device	Package	Pins	Site	Reel Diameter (mm)	Reel Width (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65HVD30DR	D	8	SITE 41	330	12	6.9	5.4	2.0	8	12	Q1
SN65HVD31DR	D	8	SITE 41	330	12	6.9	5.4	2.0	8	12	Q1
SN65HVD32DR	D	8	SITE 41	330	12	6.9	5.4	2.0	8	12	Q1
SN65HVD34DR	D	14	SITE 60	330	16	6.5	9.0	2.1	8	16	Q1
SN65HVD35DR	D	14	SITE 60	330	16	6.5	9.0	2.1	8	16	Q1

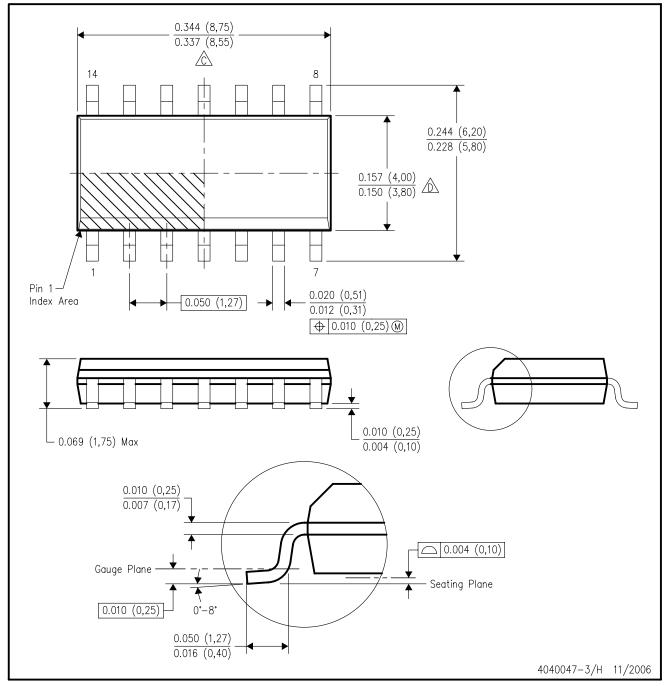




Device	Package	Pins	Site	Length (mm)	Width (mm)	Height (mm)
SN65HVD30DR	D	8	SITE 41	342.9	336.6	0.0
SN65HVD31DR	D	8	SITE 41	346.0	346.0	0.0
SN65HVD32DR	D	8	SITE 41	346.0	346.0	0.0
SN65HVD34DR	D	14	SITE 60	346.0	346.0	0.0
SN65HVD35DR	D	14	SITE 60	346.0	346.0	0.0

D (R-PDSO-G14)

PLASTIC SMALL-OUTLINE PACKAGE



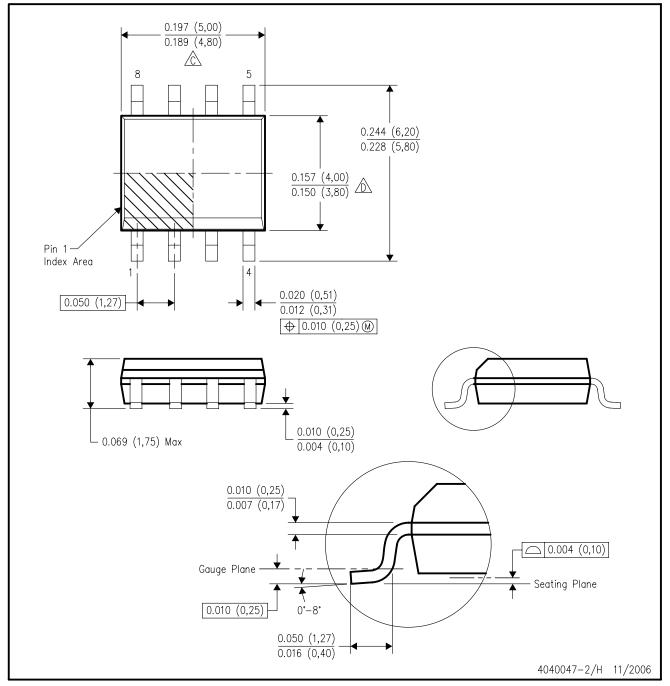
NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 (0,15) per end.
- Body width does not include interlead flash. Interlead flash shall not exceed .017 (0,43) per side.
- E. Reference JEDEC MS-012 variation AB.



D (R-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 (0,15) per end.
- Body width does not include interlead flash. Interlead flash shall not exceed .017 (0,43) per side.
- E. Reference JEDEC MS-012 variation AA.



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